

1. In a spectral ellipsometer having a source of multi-wavelength light, an optical system for directing the light, and a detecting optical system for receiving light after contact with a sample surface, the improvement comprising:

4 an optical element for receiving the multi-wavelength light directed from  
5 the optical system and focusing the multiple wavelength light onto a single spot on the  
6 sample surface.

1            2.        The spectral ellipsometer of Claim 1 wherein the optical element is a  
2        spherical prism.

1            3.        The spectral ellipsometer of Claim 1 wherein the optical element is a  
2        polarizing prism with at least one curved surface for transmitting the multi-wavelength  
3        light.

4. In a spectral ellipsometer, which includes a light incidence optical system for achieving spot incidence of polarization light of multi-wavelengths onto a sample surface and a detecting optical system for outputting information concerning the sample surface based on an amount of change in elliptical polarization reflected by the sample surface, the improvement comprising a prism polarizer employed in the light incidence optical system with a curved light-incident surface and a curved light-outgoing surface that is orthogonal with respect to a progressing direction of the respective direction of incident and outgoing light.

